

FORM PTO-892 (REV. 2-92)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	SERIAL NO. 08/111,298	GROUP ART UNIT ZSU6	ATTACHMENT TO PAPER NUMBER 4
NOTICE OF REFERENCES CITED		APPLICANT(S) COATES		

U.S. PATENT DOCUMENTS

	DOCUMENT NO.	DATE	NAME	CLASS	SUB-CLASS	FILING DATE IF APPROPRIATE
A	4035085	7.77	SEINER	356	448	
B	4455090	6.84	ROBERTS	356	448	
C	4575252	3.86	AKIYAMA	250	228	
D	4899055	2.90	ADAMS	250	372	5/12/88
E	5101111	3.92	KONDO	250	560	7/6/90
F	5120966	6.92	KONDO	250	372	2/6/91
G						
H						
I						
J						
K						

FOREIGN PATENT DOCUMENTS

	DOCUMENT NO.	DATE	COUNTRY	NAME	CLASS	SUB-CLASS	PERTINENT SHTS. DWG.	PP. SPEC.
L	6413438	1.89	JAPAN	MINAGAWA et al	250	372		
M								
N								
O								
P								
Q								

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

R	" MEASUREMENT "
S	BARKLEY, JOHN R. "MEASUREMENT AND ANALYSIS OF REFERENCE SPECTRA OF SiP ₂ " APPLIED OPTICS Vol. 11 No. 9, (Sept 1972) pp. 1928-1935.
T	
U	

EXAMINER

DATE

22 DEC 1993

* A copy of this reference is not being furnished with this office action.
(See Manual of Patent Examining Procedure, section 707.05 (a).)